MBX2 Hipot in Helium

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	01/31/2004

Test Date: 12/01/2004

Test Time: 12:47:30 AM

User Name: Glen Koreby

Device Tested

Model Number: LBX in helium

Serial Number: Box D

Setup Filename:

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand M-1,2,3,5,7	28	1	Pass	Pass	60.0s	1.40KV	0.0microamps
2	DC Withstand N 4,5,6,7	28	2	Pass	Pass	60.0s	1.40KV	0.0microamps
3	DC Withstand M 4, N1, N2 N3	28	3	Pass	Pass	60.0s	0.65KV	0.0microamps

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	01/31/2004

Test Date: 12/01/2004

Test Time: 01:09:29 AM

User Name: Glen Koraly

Device Tested MBX2

Model Number: LBX 19 pin connector 1-8 pins INHELIUM

Serial Number: BoxD

Setup Filename:

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	29	1	Pass	Pass	60.0s	0.20KV	0.0microamps

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	01/31/2004

Test Date: 12/07/2004

Test Time: 10:34:34 PM

User Name: D. [illegible]

Device Tested

Model Number: Temp. Sensor Connector

Serial Number: Box D

Setup Filename:

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	30	1	Pass	Pass	60.0s	0.20KV	0.0microamps